

FDG315N

N-Channel Logic Level PowerTrench® MOSFET

General Description

This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

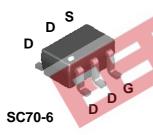
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

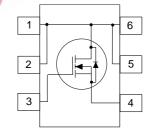
Applications

- DC/DC converter
- Load switch
- Power Management

Features

- 2 A, 30 V. $R_{DS(ON)} = 0.12~\Omega$ @ $V_{GS} = 10~V$ $R_{DS(ON)} = 0.16~\Omega$ @ $V_{GS} = 4.5~V$.
- Low gate charge (2.1nC typical).
- High performance trench technology for extremely low $R_{\rm psymh}$.
- Compact industry standard SC70-6 surface mount package.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	2	Α
	- Pulsed		6	
P_D	Power Dissipation for Single Operation	(Note 1a)	0.75	W
		(Note 1b)	0.48	
T_J , T_{stg}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

Thornia Onaractoriotico					
Rein	Thermal Resistance, Junction-to-Ambient	(Note 1b)	260	°C/W	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
. 15	FDG315N	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		26		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate-Body Leakage Forward	V _{GS} = 16 V, V _{DS} = 0 V			100	nA
I _{GSS}	Gate-Body Leakage Reverse	V _{GS} = -16 V, V _{DS} = 0 V			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1	1.8	3	V
$\Delta V_{GS(th)} = \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		-4		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 2 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 2 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = 4.5 \text{ V}, I_D = 1.7 \text{ A}$	2_	0.100 0.140 0.130	0.12 0.20 0.16	Ω
I _{D(on)}	On-State Drain Current	V _{GS} = 4.5 V, V _{DS} = 5 V	3			Α
G _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 2 \text{ A}$	-10	5		S
Dynamic	Characteristics	237				
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$		220		pF
Coss	Output Capacitance	f = 1.0 MHz		50		pF
C _{rss}	Reverse Transfer Capacitance			20		pF
Switchin	g Characteristics (Note 2)					
I _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, I_D = 1 \text{ A},$		3	6	ns
t _r	Turn-On Rise Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		11	22	ns
t _{d(off)}	Turn-Off Delay Time	1		7	14	ns
t _f	Turn-Off Fall Time			3	6	ns
Qg	Total Gate Charge	V _{DS} = 15 V, I _D = 2 A,		2.1	4	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		0.8		nC
Q _{gd}	Gate-Drain Charge			0.7		nC
Drain-Sc	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Sourc				0.42	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 0.42 \text{ A}$ (Note 2)		0.7	1.2	V

^{1.} R_{6JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

a) 170°C/W when mounted on a 1 in² pad of 2oz copper.

b) 260 $^{\circ}\text{C/W}$ when mounted on a minimum pad.

^{2.} Pulse Test: Pulse Width $\leq\!300~\mu\text{s},$ Duty Cycle $\leq\!2.0\%$

Typical Characteristics

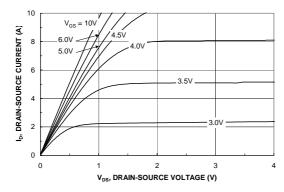


Figure 1. On-Region Characteristics.

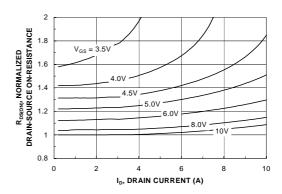


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

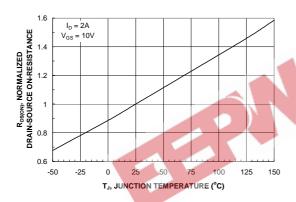


Figure 3. On-Resistance Variation with Temperature.

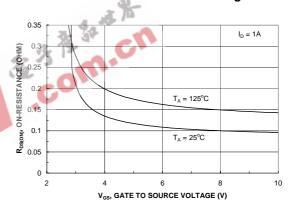


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

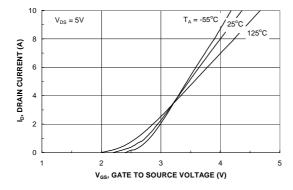


Figure 5. Transfer Characteristics.

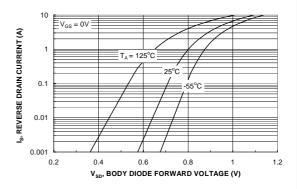
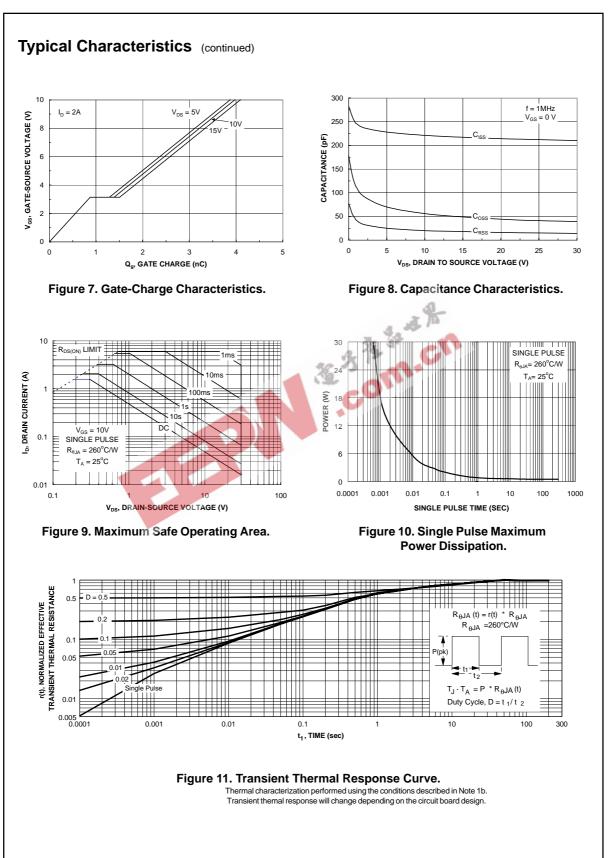


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.



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